Se	arch No	tes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/811,504	HYEON ET AL.
Examiner	Art Unit
Ardith E Hertzog	1754

	SEAR	CHED	
Class	Subclass	Date	Examiner
423	299,351, 509,561.1, 592.1,622	2005	AEH
977	DIG. 1	2005	AEH
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
eDAN inventor search	10/5/2005	AEH
EAST searches of DERWENT; USPAT/USPGPUB; &/or EPO/JPO/IBM_TDB databases (see attached strategy)	10/5,6,	AEH
reviewed related copending appln. 10/641,394 (1 common inventor, same assignee)	10/14,16	AEH